MOTOROLA
SEMICONDUCTOR
TECHNICAL DATA

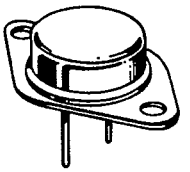
2N6377 thru 2N6379

HIGH-POWER PNP SILICON TRANSISTORS

. . . designed for use in industrial-military power amplifier and switching circuit applications.

- High Collector Emitter Sustaining Voltage –
  $V_{CEO(sus)}$ = 80 Vdc (Min) – 2N6377
  = 100 Vdc (Min) – 2N6378
  = 120 Vdc (Min) – 2N6379
- High DC Current Gain –
  h_{FE} = 30-120 @ I_C = 20 Adc
  = 10 (Min) @ I_C = 50 Adc
- Low Collector-Emitter Saturation Voltage –
  $V_{CE(sat)}$ = 1.0 Vdc (Max) @ I_C = 20 Adc
- Fast Switching Times @ I_C = 20 Adc
  t_r = 0.35 μs (Max)
  t_s = 0.8 μs (Max)
  t_f = 0.25 μs (Max)
- Complement to 2N6274–77

50 AMPERE
POWER TRANSISTORS
PNP SILICON
80, 100, 120 VOLTS
250 WATTS



* MAXIMUM RATINGS

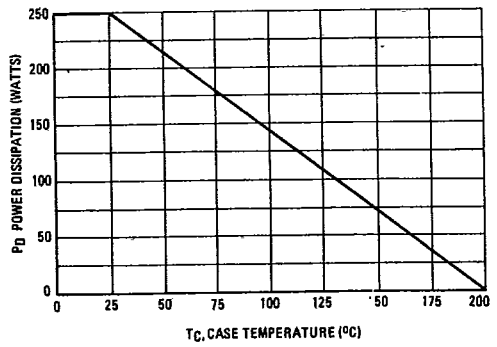
Rating	Symbol	2N6377	2N6378	2N6379	Unit
Collector-Base Voltage	V_{CB}	100	120	140	Vdc
Collector-Emitter Voltage	V_{CEO}	80	100	120	Vdc
Emitter-Base Voltage	V_{EB}	← 6.0 →			Vdc
Collector Current – Continuous Peak	I_C	← 50 → ← 100 →			Adc
Base Current	I_B	← 20 →			Adc
Total Device Dissipation @ T_C = 25°C Derate above 25°C	P_D	← 250 → ← 1.43 →			Watts W/°C
Operating and Storage Junction Temperature Range	T_J,T_{stg}	← -65 to +200 →			°C

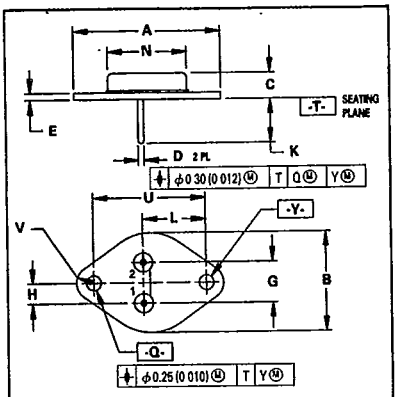
THERMAL CHARACTERISTICS

Characteristic	Symbol	Max	Unit
Thermal Resistance, Junction to Case	θ_{JC}	0.7	°C/W

*Indicates JEDEC Registered Data.

FIGURE 1 – POWER DERATING





STYLE 1:
PIN 1. BASE
2. EMITTER
CASE. COLLECTOR

DIM	MILLIMETERS MIN	MILLIMETERS MAX	INCHES MIN	INCHES MAX
A	38.86 REF		1.530 REF	
B	25.15	26.67	0.990	1.050
C	6.35	8.25	0.250	0.325
D	1.45	1.60	0.057	0.063
E	1.53	1.77	0.060	0.070
G	10.92 BSC		0.430 BSC	
H	5.46 BSC		0.215 BSC	
K	11.18	12.19	0.440	0.480
L	16.89 BSC		0.665 BSC	
N	19.31	21.08	0.760	0.830
Q	3.84	4.19	0.151	0.165
U	30.15 BSC		1.187 BSC	
V	3.33	4.77	0.131	0.188

CASE 197A-02
TO-204AE
(TO-3)

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2N6377 thru 2N6379

T-33-23

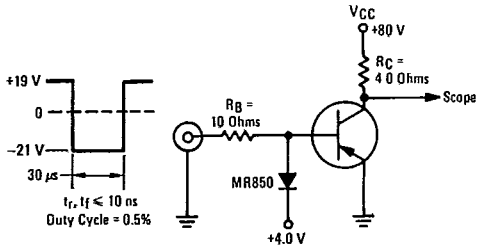
ELECTRICAL CHARACTERISTICS (T_C = 25°C unless otherwise noted)

Characteristic		Symbol	Min	Max	Unit
***OFF CHARACTERISTICS**					
Collector-Emitter Sustaining Voltage (1) (I_C = 50 mAdc, I_B = 0)	2N6377	$V_{CEO(sus)}$	80	–	Vdc
	2N6378		100	–	
	2N6379		120	–	
Collector Cutoff Current		I_{CEO}			μAdc
(V_{CE} = 50 Vdc, I_B = 0)	2N6377		–	50	
(V_{CE} = 60 Vdc, I_B = 0)	2N6378		–	50	
(V_{CE} = 70 Vdc, I_B = 0)	2N6379		–	50	
Collector Cutoff Current		I_{CEX}			
(V_{CE} = 90% Rated V_{CB}, $V_{BE(off)}$ = 1.5 Vdc)			–	10	μAdc
(V_{CE} = 90% Rated V_{CB}, $V_{BE(off)}$ = 1.5 Vdc, T_C = 150°C)			–	1.0	mAdc
Emitter Cutoff Current (V_{EB} = 6.0 Vdc, I_C = 0)		I_{EBO}	–	100	μAdc
***ON CHARACTERISTICS** (1)					
DC Current Gain		h_{FE}			–
(I_C = 1.0 Adc, V_{CE} = 4.0 Vdc)			50	–	
(I_C = 20 Adc, V_{CE} = 4.0 Vdc)			30	120	
(I_C = 50 Adc, V_{CE} = 4.0 Vdc)			10	–	
Collector-Emitter Saturation Voltage		$V_{CE(sat)}$	–		Vdc
(I_C = 20 Adc, I_B = 2.0 Adc)			–	1.2	
(I_C = 50 Adc, I_B = 10 Adc)			–	3.0	
Base-Emitter Saturation Voltage		$V_{BE(sat)}$			Vdc
(I_C = 20 Adc, I_B = 2.0 Adc)			–	1.8	
(I_C = 50 Adc, I_B = 10 Adc)			–	3.5	
DYNAMIC CHARACTERISTICS					
*Current-Gain – Bandwidth Product (2) (I_C = 1.0 Adc, V_{CE} = 10 Vdc, f_{test} = 10 MHz)		f_T	30	–	MHz
*Output Capacitance (V_{CB} = 10 Vdc, I_E = 0, f = 0.1 MHz)		C_{ob}	–	1500	pF
***SWITCHING CHARACTERISTICS** (Figure 2)					
Rise Time	(V_{CC} = 80 Vdc, I_C = 20 Adc, I_{B1} = I_{B2} = 2.0 Adc)	t_r	–	0.35	μs
Storage Time		t_s	–	0.80	μs
Fall Time		t_f	–	0.25	μs

*Indicates JEDEC Registered Data.

(1) Pulse Test: Pulse Width = 300 μs, Duty Cycle = 2.0%. (2) $f_T = |h_{fe}| \cdot f_{test}$

FIGURE 2 – SWITCHING TIMES TEST CIRCUIT



Note: For information on Figures 3 & 6, R_B and R_C were varied to obtain desired test conditions.

FIGURE 3 – TURN ON TIME

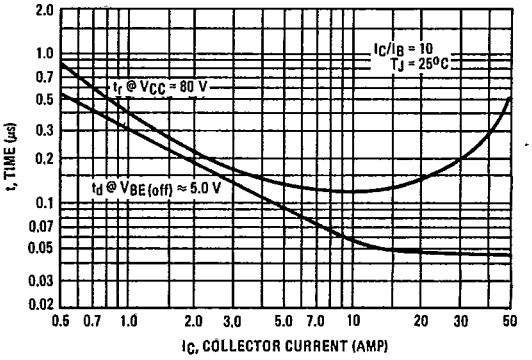


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FIGURE 4 – THERMAL RESPONSE

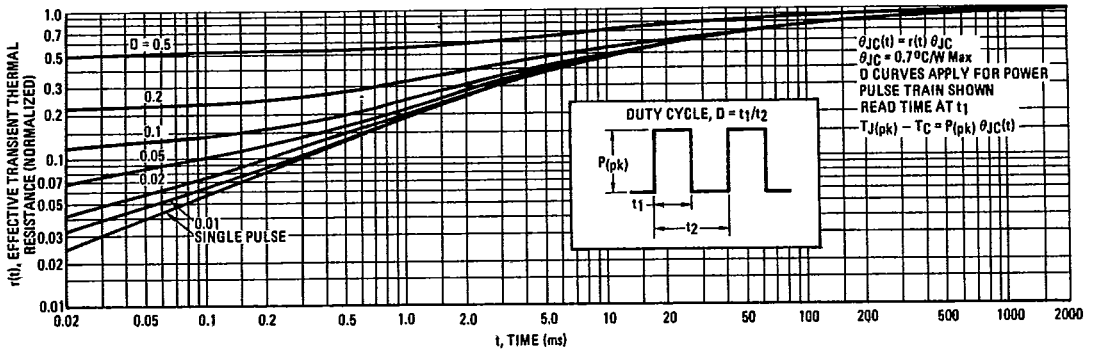
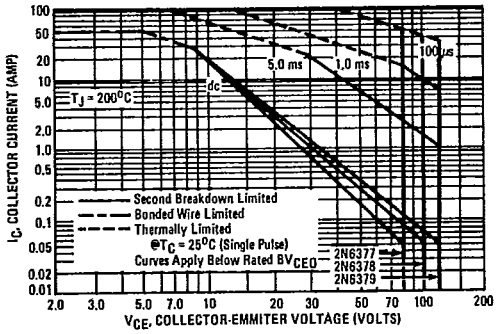


FIGURE 5 – ACTIVE REGION SAFE OPERATING AREA



There are two limitations on the power handling ability of a transistor: average junction temperature and second breakdown. Safe operating area curves indicate I_C-V_{CE} limits of the transistor that must be observed for reliable operation; i.e., the transistor must not be subjected to greater dissipation than the curves indicate.

The data of Figure 5 is based on $T_{J(pk)} = 200^{\circ}C$; T_C is variable depending on conditions. Second breakdown pulse limits are valid for duty cycles to 10% provided $T_{J(pk)} \leq 200^{\circ}C$. $T_{J(pk)}$ may be calculated from the data in Figure 4. At high case temperatures, thermal limitations will reduce the power that can be handled to values less than the limitations imposed by second breakdown.

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FIGURE 6 – TURN-OFF TIME

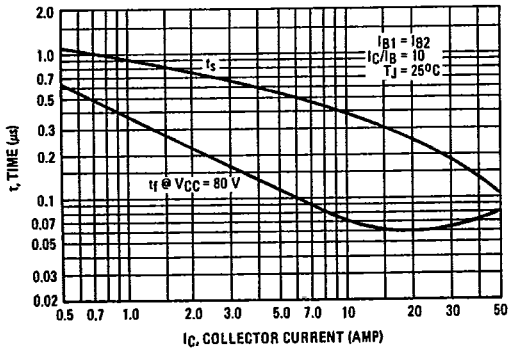

FIGURE 7 – CAPACITANCE

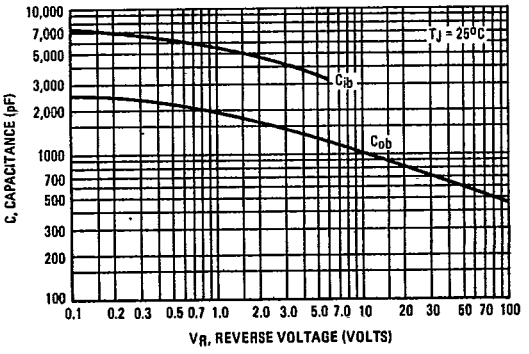

FIGURE 8 – DC CURRENT GAIN

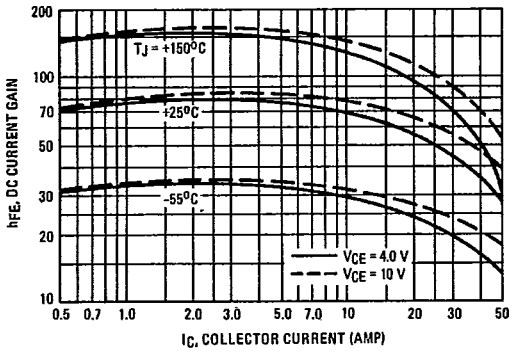

FIGURE 9 – COLLECTOR SATURATION REGION

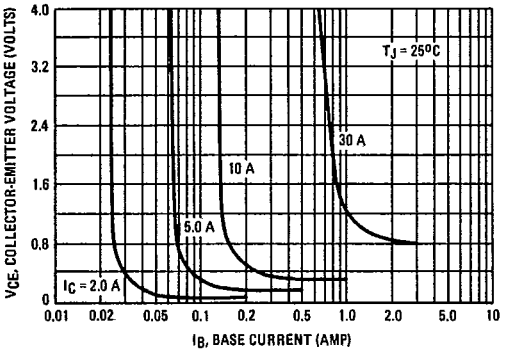

FIGURE 10 – "ON" VOLTAGES

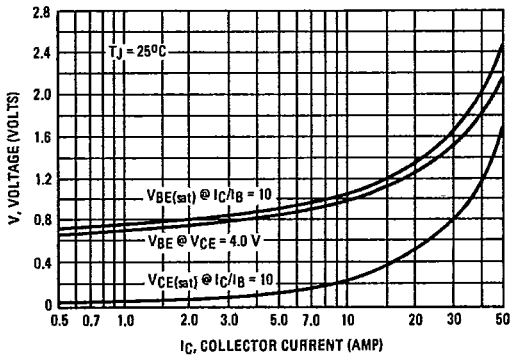

FIGURE 11 – TEMPERATURE COEFFICIENTS

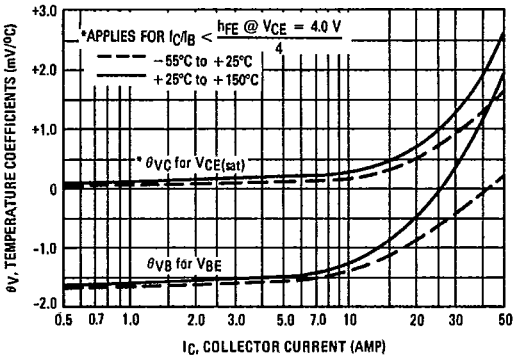

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FIGURE 12 – COLLECTOR CUT-OFF REGION

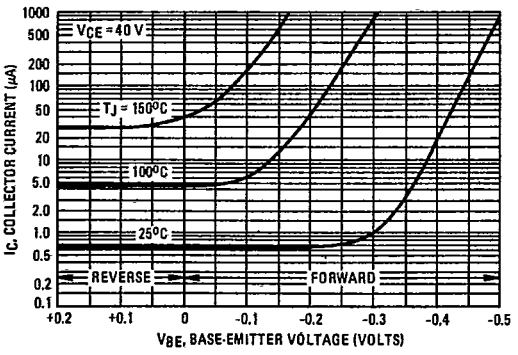

FIGURE 13 – BASE CUTOFF REGION